

<b>Notic o f Reference s Cited</b>			Application/Control No. 09/406,663	Applicant(s)/Patent Under Reexamination KNEBEL ET AL.
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,483,327 ✓	11-2002	Bruce et al.	324/752
	C	US-5,251,159 ✓	10-1993	Rowson, James A.	703/14
	D	US-5,555,201 ✓	09-1996	Dangelo et al.	716/1
	E	US-5,270,643 ✓	12-1993	Richardson et al.	324/751
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	G	US-6,342,701 ✓	01-2002	Kash, Jeffrey A.	250/458.1
	H	US-6,442,720 ✓	08-2002	Koprowski et al.	714/726
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Diagnosis and Characterization of Timing-Related Defects by Time-Dependent Light Emission", D. Knebel et al, International Test Conference, IEEE, August 1998 ✓
	V	"Failure Analysis of ULSI circuits Using Photon Emission", Y. Uraoka, IEEE Log Number 9211664, IEEE 1993 ✓
	W	"The Attack of the "Holey Shmoos": A Case Study of Advanced DFD and Picosecond Imaging Circuit Analysis (PICA)", W. Huott, ITC International Test Conference, IEEE, January 1999 ✓
	X	"An Integrated Photon Emission Microscope and MOSFET Caharterization System of Combinerd Microscopic and Macroscopic Device Analysis", T.H. Ng, IEEE Proceedings fo 7 <sup>th</sup> IPFA '99, August 1999 ✓

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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	C	US-6,263,301 ✓	07-2001	Cox et al.	703/14
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	K	US-			
	L	US-			
	M	US-			

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	V	"Picosecond Imaging Circuit Analysis of the POWER3 Clock Distribution", P.N. Sandra, 1999 IEEE International Solid-State Conference, June 1999. ✓
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